ULVAC-PHI on-line Seminar

October 31, 2024 2:00 PM to 3:00 PM (JST)

TOF-SIMS Application Seminar Registration !

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Seminar Summary

The time-of-flight secondary ion mass spectrometry (TOF-SIMS) is a surface analysis technique that due to the high detection sensitivity and high mass and lateral resolution can provide elemental and molecular information of a large variety of samples, such as metals, semiconductors, batteries, polymers and biomaterials.

PHI nanoTOF 3$^+$, the latest model of TOF-SIMS from ULVAC-PHI, Inc., can reach the spatial resolution of 50 nm and can be equipped with the tandem MS option, making it a unique analytical instrument able to unravel even the most complex molecular distributions. In this seminar it will be given an overview of PHI nanoTOF 3$^+$ latest applications, showing how this instrument has the potential to lead the research on the latest trends in material science and manufacturing.

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